

**Application Information**

Applicant Type:: Regular  
Subject Matter:: Utility  
Suggested Classification::  
Suggested Group Art Unit::  
CD-ROM or CD-R?:: None  
Title:: Verfahren zur Messung von  
Kennwerten, insbesondere der  
Temperature eines  
mehrschichtigen Materials  
während des Schichtenaufbaus  
Attorney Docket Number:: 101215-75  
Request for Early Publication?:: No  
Request for Non-Publication?:: No  
Suggested Drawing Sheets::  
Total Drawing Sheets:: 5  
Small Entity:: Yes  
Petition included?::  
Secrecy Order in Parent Appl.?::

**Inventor Information**

Inventor Authority type:: Inventor  
Primary Citizenship Country:: Germany  
Status:: Full Capacity  
Given Name:: Zettler  
Middle Name::  
Family Name:: Jörg-Thomas  
City of Residence:: Berlin

Application Data Sheet

Country of Residence:: Germany  
Street:: Ossietzkystrasse 2  
City:: Berlin  
Postal or Zip Code:: 13187  
Country:: Germany

Inventor Authority type:: Inventor  
Primary Citizenship Country:: Germany  
Status:: Full Capacity  
Given Name:: Haberland

Middle Name::  
Family Name:: Kolja  
City of Residence:: Berlin  
Country of Residence:: Germany  
Street:: Ahornstrasse 8b  
City:: Berlin  
Postal or Zip Code:: 12163  
Country:: Germany

**Correspondence Information**

Correspondence Customer Number:: 27387  
Phone Number:: 212-808-0700  
Fax Number:: 212-808-0844  
E-Mail address:: bslonda@nmmlaw.com

**Representative Information**

Representative Customer Number:: 27387

**Domestic Priority Information**

Application:: Continuity Type:: Parent Patent  
Application:: Filing Date::  
None

**Foreign Priority Information**

Country:: Application Number:: Filing Date::  
Germany 100 61 168.0 November 30, 2000

**Assignee Information**

Assignee Name:: LayTec Gesellschaft für in-situ und  
nano-Sensorik mbH  
Street:: Hardenberstrasse 36  
City:: Berlin  
Country:: Germany  
Postal or Zip Code:: 10623